

### **Automated software-based in-field self-test program synthesis**

**Jasnetski, Artjom; Ubar, Raimund-Johannes; Tšertov, Anton** International journal of microelectronics and computer science 2017 / p. 57-64 : ill

### **Automated software-based self-test generation for microprocessors**

**Jasnetski, Artjom; Ubar, Raimund-Johannes; Tšertov, Anton** Proceedings of the 24st International Conference Mixed Design of Integrated Circuits and Systems : MIXDES 2017 : Bydgoszcz, Poland, June 19-21, 2014 2017 / p. 453-458 : ill  
<https://doi.org/10.23919/MIXDES.2017.8005252>

### **High-level modeling and testing of multiple control faults in digital systems**

**Jasnetski, Artjom; Oyeniran, Adeboye Stephen; Tšertov, Anton; Schölzel, Mario; Ubar, Raimund-Johannes** Formal proceedings of the 2016 IEEE 19th International Symposium on Design and Diagnostics of Electronic Circuits & Systems (DDECS) : April 20-22, 2016, Košice, Slovakia 2016 / [6] p. : ill <http://dx.doi.org/10.1109/DDECS.2016.7482445>

### **High-level test data generation for software based self-test in microprocessors**

**Oyeniran, Adeboye Stephen; Jasnetski, Artjom; Tšertov, Anton; Ubar, Raimund-Johannes** 2017 6th Mediterranean Conference on Embedded Computing (MECO) : including ECYPS'2017 : proceedings : research monograph : Bar, Montenegro, June 11th-15th, 2017 2017 / p. 86-91 : ill <https://doi.org/10.1109/MECO.2017.7977167>

### **In-system programming of non-volatile memories on microprocessor-centric boards**

**Tšertov, Anton; Devadze, Sergei; Jutman, Artur; Jasnetski, Artjom** International journal of microelectronics and computer science 2014 / p. 25-34 : ill

### **Laboratory framework TEAM for investigating the dependability issues of microprocessor systems**

**Jasnetski, Artjom; Tšertov, Anton; Ubar, Raimund-Johannes; Kruus, Helena** 10th European Workshop on Microelectronics Education : EWME 2014 : May 14-16, 2014, Tallinn, Estonia 2014 / p. 80-83 : ill

### **New fault models and self-test generation for microprocessors using High-Level Decision Diagrams**

**Jasnetski, Artjom; Raik, Jaan; Tšertov, Anton; Ubar, Raimund-Johannes** 2015 IEEE 18th International Symposium on Design and Diagnostics of Electronic Circuits & Systems DDECS 2015 : 22-24 April 2015, Belgrade, Serbia : proceedings 2015 / p. 251-254 : ill

### **On automatic software-based self-test program generation based on high-Level decision diagrams**

**Jasnetski, Artjom; Ubar, Raimund-Johannes; Tšertov, Anton** LATS 2016 : 17th IEEE Latin-American Test Symposium, Foz do Iguaçu, Brazil, 6th-9th April 2016 2016 / p. 177 <http://dx.doi.org/10.1109/LATW.2016.7483357>

### **On in-system programming of non-volatile memories**

**Tšertov, Anton; Devadze, Sergei; Jutman, Artur; Jasnetski, Artjom** Proceedings of the 20th International Conference Mixed Design of Integrated Circuits and Systems : MIXDES 2013, Gdynia, Poland, June 20-22, 2013 2013 / p. 408-413 : ill

### **On in-system programming of non-volatile memories**

**Tšertov, Anton; Devadze, Sergei; Jutman, Artur; Jasnetski, Artjom** International journal of microelectronics and computer science 2013 / p. 72-78 : ill

### **Software-based self-test for microprocessors with high-level decision diagrams = Mikroprotsessorite tarkvara-põhine enesetestimine kõrgtasandi otsustusdiagrammide põhjal**

**Jasnetski, Artjom** 2018 <https://digi.lib.ttu.ee/ii/?10629> [https://www.ester.ee/record=b5151486\\*est](https://www.ester.ee/record=b5151486*est)

### **Software-based self-test generation for microprocessors with high-level decision diagrams**

**Jasnetski, Artjom; Ubar, Raimund-Johannes; Tšertov, Anton; Brik, Marina** Proceedings of the Estonian Academy of Sciences 2014 / p. 48-61 : ill [https://artiklid.elnet.ee/record=b2665215\\*est](https://artiklid.elnet.ee/record=b2665215*est) <https://doi.org/10.3176/proc.2014.1.08> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

### **Software-based self-test generation for microprocessors with high-level decision diagrams**

**Ubar, Raimund-Johannes; Tšertov, Anton; Jasnetski, Artjom; Brik, Marina** LATW2014 : 15th IEEE Latin-American Test Workshop : Fortaleza, Brazil, March 12th-15th, 2014 2014 / [6] p. : ill

### **Software-based self-test with decision diagrams for microprocessors**

**Ubar, Raimund-Johannes; Jasnetski, Artjom; Tšertov, Anton; Oyeniran, Adeboye Stephen** 2018